

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

	Jong Shik Yoon, et al.	Docket No.:	TI-37043
Serial No:	10/825,343	Filed:	04/15/2004
Art Unit:	2813	Examiner:	David S. Blum
Customer No.:	23494	Conf. No.:	8658
Title:	Minimizing Transistor Variations Due to Shallow Trench Isolation Stress		

AMENDMENT UNDER 37 CFR 1.111

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATION OF TRANSMISSION

I hereby certify that the following papers are being electronically transmitted to the U.S. Patent and Trademark Office on 11/14/2006.

/Jacqueline J. Garner/
Jacqueline J. Garner
Reg. No. 36,144

Dear Sir:

The following amendments and remarks are offered in response to the Examiner's Office Action dated June 14, 2006. They are respectfully submitted as a full and complete response to that Action.

Please amend the above-referenced application as follows:

There are no **Amendments to the Specification**.

Amendments to the Claims are reflected in the listing of claims that begin on page 2 of this paper.

There are no **Amendments to the Drawings**.

The **Remarks** begin on page 4.